I²C®-Compatible, Wide Bandwidth, Hex 2:1 Multiplexer

ADG796A

FEATURES

- Bandwidth: 325 MHz
- Low insertion loss and on resistance: 2.6 Ω typical
- On resistance flatness: 0.3 Ω typical
- Single 3 V/5 V supply operation
- 3.3 V analog signal range (5 V supply, 75 Ω load)
- Low quiescent supply current: 1 nA typical
- Fast switching times: t_{ON} = 186 ns, t_{OFF} = 177 ns
- I²C-compatible interface
- Compact 24-lead LFCSP
- ESD protection
  - 4 kV human body model
  - 200 V machine model
  - 1 kV field-induced charged device model

APPLICATIONS

- S-Video RGB/YPbPr video switches
- HDTV
- Projection TV
- DVD-R/RW
- AV receivers

FUNCTIONAL BLOCK DIAGRAM

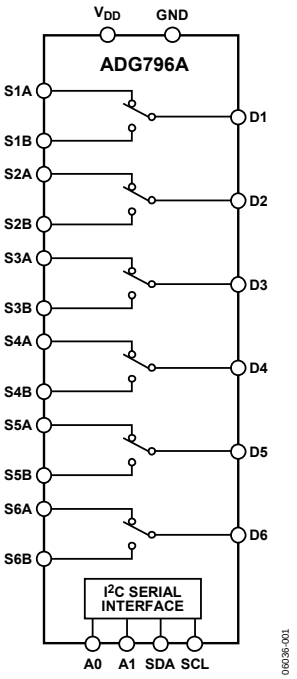


Figure 1.

GENERAL DESCRIPTION

The ADG796A is a monolithic CMOS device comprising six 2:1 multiplexer/demultiplexers controlled by a standard I²C serial interface. The CMOS process provides ultralow power dissipation, yet offers high switching speed and low on resistance.

The on resistance profile is very flat over the full analog input range, and wide bandwidth ensures excellent linearity and low distortion. These features, combined with a wide input signal range, make the ADG796A the ideal switching solution for a wide range of TV applications including S-Video, YPbPr, and RGB video switches.

The switches conduct equally well in both directions when on. In the off condition, signal levels up to the supplies are blocked. The ADG796A switches exhibit break-before-make switching action.

The integrated I²C interface provides a large degree of flexibility in the system design. It has two user adjustable I²C address pins that allow up to four devices on the same bus. This allows the user to expand the capability of the device by increasing the size of the switching array.

The ADG796A operates from a single 3 V or 5 V supply voltage and is available in a compact 4 mm × 4 mm body, 24-lead, Pb-free LFCSP.

PRODUCT HIGHLIGHTS

1. Wide bandwidth: 325 MHz.
2. Ultralow power dissipation.
3. Extended input signal range.
4. Integrated I²C serial interface.
5. Compact 4 mm × 4 mm, 24-lead, Pb-free LFCSP.
6. ESD protection tested as per ESD Association standards:
   - 4 kV HBM (ANSI/ESD STM5.1-2001)
   - 200 V MM (ANSI/ESD STM5.2-1999)
   - 1 kV FICDM (ANSI/ESD STM5.3.1-1999)

Rev. 0
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One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A.
Tel: 781.329.4700 **www.analog.com**
Fax: 781.461.3113 **©2006 Analog Devices, Inc. All rights reserved.**

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REVISION HISTORY

7/06—Revision 0: Initial Version

SPECIFICATIONS

V_{DD} = 5 V ± 10%, GND = 0 V, T_A = −40°C to +85°C, unless otherwise noted.

Table 1.

Parameter	Conditions	Min	Typ[1]	Max	Unit
ANALOG SWITCH					
Analog Signal Range[2]	$V_S = V_{DD}$, R_L = 1 MΩ	0		4	V
	$V_S = V_{DD}$, R_L = 75 Ω	0		3.3	V
On Resistance, R_{ON}	V_D = 0 V, I_{DS} = −10 mA, see Figure 18		2.2	3.5	Ω
	V_D = 0 V to 1 V, I_{DS} = −10 mA, see Figure 18			4	Ω
On Resistance Matching Between Channels, ΔR_{ON}	V_D = 0 V I_{DS} = −10 mA		0.15	0.5	Ω
	V_D = 1 V I_{DS} = −10 mA			0.6	Ω
On Resistance Flatness, $R_{FLAT(ON)}$	V_D = 0 V to 1 V, I_{DS} = −10 mA		0.3	0.55	Ω
LEAKAGE CURRENTS					
Source Off Leakage ($I_{S(OFF)}$)	V_D = 4 V/1 V, V_S = 1 V/4 V, see Figure 19		±0.25		nA
Drain Off Leakage ($I_{D(OFF)}$)	V_D = 4 V/1 V, V_S = 1 V/4 V, see Figure 19		±0.25		nA
Channel On Leakage ($I_{D(ON)}$, $I_{S(ON)}$)	$V_D = V_S$ = 4 V/1 V, see Figure 20		±0.25		nA
DYNAMIC CHARACTERISTICS[3]					
t_{ON}, t_{ENABLE}	C_L = 35 pF, R_L = 50 Ω, V_S = 2 V, see Figure 24		186	250	ns
t_{OFF}, $t_{DISABLE}$	C_L = 35 pF, R_L = 50 Ω, V_S = 2 V, see Figure 24		177	240	ns
Break-Before-Make Time Delay, t_D	C_L = 35 pF, R_L = 50 Ω, $V_{S1} = V_{S2}$ = 2 V, see Figure 25	1	3		ns
Off Isolation	f = 10 MHz, R_L = 50 Ω, see Figure 22		−60		dB
Channel-to-Channel Crosstalk	f = 10 MHz, R_L = 50 Ω, see Figure 23				
Same Multiplexer			−55		dB
Different Multiplexer			−70		dB
−3 dB Bandwidth	R_L = 50 Ω, see Figure 21		325		MHz
THD + N	R_L = 100 Ω		0.14		%
Charge Injection	C_L = 1 nF, V_S = 0 V, see Figure 26		5		pC
$C_{S(OFF)}$			10		pF
$C_{D(OFF)}$			13		pF
$C_{D(ON)}$, $C_{S(ON)}$			27		pF
Power Supply Rejection Ratio, PSRR	f = 20 kHz		70		dB
Differential Gain Error	CCIR330 test signal		0.32		%
Differential Phase Error	CCIR330 test signal		0.44		Degrees
LOGIC INPUTS (A0, A1, A2)[3]					
Input High Voltage, V_{INH}		2.0			V
Input Low Voltage, V_{INL}				0.8	V
Input Current, I_{INL} or I_{INH}	V_{IN} = 0 V to V_{DD}		0.005	±1	μA
Input Capacitance, C_{IN}			3		pF
LOGIC INPUTS (SCL, SDA)[3]					
Input High Voltage, V_{INH}		0.7 × V_{DD}		V_{DD} + 0.3	V
Input Low Voltage, V_{INL}		−0.3		+0.3 × V_{DD}	V
Input Leakage Current, I_{IN}	V_{IN} = 0 V to V_{DD}		+0.005	±1	μA
Input Hysteresis			0.05 × V_{DD}		V
Input Capacitance, C_{IN}			3		pF
LOGIC OUTPUTS[3]					
SDA Pin					
Output Low Voltage, V_{OL}	I_{SINK} = 3 mA			0.4	V
	I_{SINK} = 6 mA			0.6	V
Floating State Leakage Current				±1	μA
Floating State Output Capacitance				10	pF

Parameter	Conditions	Min	Typ[1]	Max	Unit
POWER REQUIREMENTS					
I_{DD}	Digital inputs = 0 V or V_{DD}, I^2C interface inactive		0.001	1	μA
	I^2C interface active, f_{SCL} = 400 kHz			0.2	mA
	I^2C interface active, f_{SCL} = 3.4 MHz			0.7	mA

[1]All typical values are at T_A = +25°C, unless otherwise stated.
[2] Guaranteed by initial characterization, not subject to production test.
[3] Guaranteed by design, not subject to production test.

V_{DD} = 3 V ± 10%, GND = 0 V, T_A = −40°C to +85°C, unless otherwise noted.

Table 2.

Parameter	Conditions	Min	Typ[1]	Max	Unit
ANALOG SWITCH					
Analog Signal Range[2]	$V_S = V_{DD}$, R_L = 1 MΩ	0		2.2	V
	$V_S = V_{DD}$, R_L = 75 Ω	0		1.7	V
On Resistance, R_{ON}	V_D = 0 V, I_{DS} = −10 mA, see Figure 18		2.2	4	Ω
	V_D = 0 V to 1 V, I_{DS} = −10 mA, see Figure 18			6	Ω
On Resistance Matching Between Channels, ΔR_{ON}	V_D = 0 V I_{DS} = −10 mA		0.15	0.6	Ω
	V_D = 1 V I_{DS} = −10 mA			1.1	Ω
On Resistance Flatness, $R_{FLAT(ON)}$	V_D = 0 V to 1 V, I_{DS} = −10 mA		0.3	2.8	Ω
LEAKAGE CURRENTS					
Source Off Leakage ($I_{S(OFF)}$)	V_D = 2 V/1 V, V_S = 1 V/2 V, see Figure 19		±0.25		nA
Drain Off Leakage ($I_{D(OFF)}$)	V_D = 2 V/1 V, V_S = 1 V/2 V, see Figure 19		±0.25		nA
Channel On Leakage ($I_{D(ON)}$, $I_{S(ON)}$)	$V_D = V_S$ = 2 V/1 V, see Figure 20		±0.25		nA
DYNAMIC CHARACTERISTICS[3]					
t_{ON}, t_{ENABLE}	C_L = 35 pF, R_L = 50 Ω, V_S = 2 V, see Figure 24		198	270	ns
t_{OFF}, $t_{DISABLE}$	C_L = 35 pF, R_L = 50 Ω, V_S = 2 V, see Figure 24		195	260	ns
Break-Before-Make Time Delay, t_D	C_L = 35 pF, R_L = 50 Ω, $V_{S1} = V_{S2}$ = 2 V, see Figure 25	1	3		ns
Off Isolation	f = 10 MHz, R_L = 50 Ω, see Figure 22		−60		dB
Channel-to-Channel Crosstalk	f = 10 MHz, R_L = 50 Ω, see Figure 23				
Same Multiplexer			−55		dB
Different Multiplexer			−70		dB
−3 dB Bandwidth	R_L = 50 Ω, see Figure 21		310		MHz
THD + N	R_L = 100 Ω		0.14		%
Charge Injection	C_L = 1 nF, V_S = 0 V, see Figure 26		2.5		pC
$C_{S(OFF)}$			10		pF
$C_{D(OFF)}$			13		pF
$C_{D(ON)}$, $C_{S(ON)}$			27		pF
Power Supply Rejection Ratio, PSRR	f = 20 kHz		70		dB
Differential Gain Error	CCIR330 test signal		0.28		%
Differential Phase Error	CCIR330 test signal		0.28		Degrees
LOGIC INPUTS (A0, A1, A2)[3]					
Input High Voltage, V_{INH}		2.0			V
Input Low Voltage, V_{INL}				0.8	V
Input Current, I_{INL} or I_{INH}	V_{IN} = 0 V to V_{DD}		0.005	±1	μA
Input Capacitance, C_{IN}			3		pF
LOGIC INPUTS (SCL, SDA)[3]					
Input High Voltage, V_{INH}		0.7 × V_{DD}		V_{DD} + 0.3	V
Input Low Voltage, V_{INL}		−0.3		+0.3 × V_{DD}	V
Input Leakage Current, I_{IN}	V_{IN} = 0 V to V_{DD}		+0.005	±1	μA
Input Hysteresis			0.05 × V_{DD}		V
Input Capacitance, C_{IN}			3		pF
LOGIC OUTPUTS [3]					
SDA Pin					
Output Low Voltage, V_{OL}	I_{SINK} = 3 mA			0.4	V
	I_{SINK} = 6 mA			0.6	V
Floating State Leakage Current				±1	μA
Floating State Output Capacitance			3		pF

Parameter	Conditions	Min	Typ[1]	Max	Unit
POWER REQUIREMENTS					
I_{DD}	Digital inputs = 0 V or V_{DD}, I^2C interface inactive		0.001	1	μA
	I^2C interface active, f_{SCL} = 400kHz			0.1	mA
	I^2C interface active, f_{SCL} = 3.4MHz			0.2	mA

[1]All typical values are at T_A = +25°C, unless otherwise stated.
[2] Guaranteed by initial characterization, not subject to production test.
[3] Guaranteed by design, not subject to production test.

I²C TIMING SPECIFICATIONS

V_{DD} = 2.7 V to 5.5 V; GND = 0 V; T_A = −40°C to +85°C, unless otherwise noted (see Figure 2 for timing diagram).

Table 3.

Parameter[1]	Conditions	Min	Max	Unit	Description
f_{SCL}	Standard mode		100	kHz	Serial clock frequency
	Fast mode		400	kHz	
	High speed mode				
	C_B = 100 pF max		3.4	MHz	
	C_B = 400 pF max		1.7	MHz	
t_1	Standard mode	4		µs	t_{HIGH}, SCL high time
	Fast mode	0.6		µs	
	High speed mode				
	C_B = 100 pF max	60		ns	
	C_B = 400 pF max	120		ns	
t_2	Standard mode	4.7		µs	t_{LOW}, SCL low time
	Fast mode	1.3		µs	
	High speed mode				
	C_B = 100 pF max	160		ns	
	C_B = 400 pF max	320		ns	
t_3	Standard mode	250		ns	$t_{SU;DAT}$, data setup time
	Fast mode	100		ns	
	High speed mode	10		ns	
t_4[2]	Standard mode	0	3.45	µs	$t_{HD;DAT}$, data hold time
	Fast mode	0	0.9	µs	
	High speed mode				
	C_B = 100 pF max	0	703	ns	
	C_B = 400 pF max	0	150	ns	
t_5	Standard mode	4.7		µs	$t_{SU;STA}$, setup time for a repeated start condition
	Fast mode	0.6		µs	
	High speed mode	160		ns	
t_6	Standard mode	4		µs	$t_{HD;STA}$, hold time (repeated) start condition
	Fast mode	0.6		µs	
	High speed mode	160		ns	
t_7	Standard mode	4.7		µs	t_{BUF}, bus free time between a stop and a start condition
	Fast mode	1.3		µs	
t_8	Standard mode	4		µs	$t_{SU;STO}$, setup time for stop condition
	Fast mode	0.6		µs	
	High speed mode	160		ns	
t_9	Standard mode		1000	ns	t_{RDA}, rise time of SDA signal
	Fast mode	20 + 0.1 C_B	300	ns	
	High speed mode				
	C_B = 100 pF max	10	80	ns	
	C_B = 400 pF max	20	160	ns	
t_{10}	Standard mode		300	ns	t_{FDA}, fall time of SDA signal
	Fast mode	20 + 0.1 C_B	300	ns	
	High speed mode				
	C_B = 100 pF max	10	80	ns	
	C_B = 400 pF max	20	160	ns	
t_{11}	Standard mode		1000	ns	t_{RCL}, rise time of SCL signal
	Fast mode	20 + 0.1 C_B	300	ns	
	High speed mode				
	C_B = 100 pF max	10	40	ns	
	C_B = 400 pF max	20	80	ns	

Parameter[1]	Conditions	Min	Max	Unit	Description
t_{11A}	Standard mode		1000	ns	t_{RCL1}, rise time of SCL signal after a repeated start condition and after
	Fast mode	20 + 0.1 C_B	300	ns	an acknowledge bit
	High speed mode				
	C_B = 100 pF max	10	80	ns	
	C_B = 400 pF max	20	160	ns	
t_{12}	Standard mode		300	ns	t_{FCL}, fall time of SCL signal
	Fast mode	20 + 0.1 C_B	300	ns	
	High speed mode				
	C_B = 100 pF max	10	40	ns	
	C_B = 400 pF max	20	80	ns	
t_{SP}	Fast mode	0	50	ns	Pulse width of suppressed spike
	High speed mode	0	10	ns	

[1] Guaranteed by initial characterization. C_B refers to capacitive load on the bus line, tr and tf measured between 0.3 VDD and 0.7 VDD.
[2] A device must provide a data hold time for SDA in order to bridge the undefined region of the SCL falling edge.

Timing Diagram

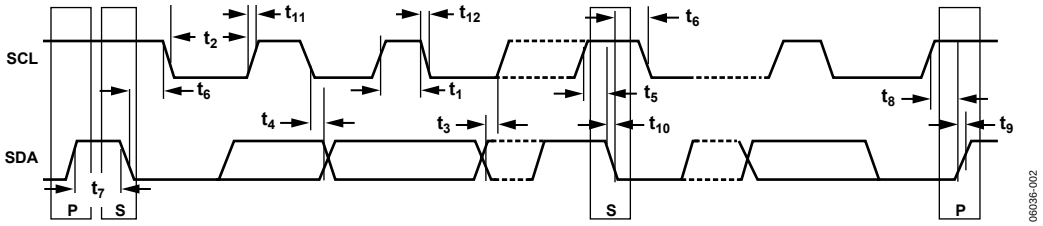


Figure 2. Timing Diagram for 2-Wire Serial Interface

ABSOLUTE MAXIMUM RATINGS

T_A = 25°C, unless otherwise noted.

Table 4.

Parameter	Rating
V_{DD} to GND	−0.3 V to +6 V
Analog, Digital Inputs	−0.3 V to V_{DD} + 0.3 V or 30 mA, whichever occurs first
Continuous Current, S or D Pins	100 mA
Peak Current, S or D Pins	300 mA (pulsed at 1 ms, 10% duty cycle max)
Operating Temperature Range	
Industrial (B Version)	−40°C to +85°C
Storage Temperature Range	−65°C to +150°C
Junction Temperature	150°C
θ_{JA} Thermal Impedance	
24-Lead LFCSP	30°C/W
Lead Temperature, Soldering (10 sec)	300°C
IR Reflow, Peak Temperature (<20 sec)	260°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Only one absolute maximum rating can be applied at any one time.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

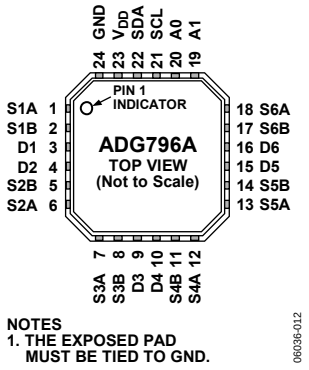


Figure 3. Pin Configuration

Table 5. Pin Function Descriptions

Pin No.	Mnemonic	Function
1	S1A	A-Side Source Terminal for Mux 1. Can be an input or output.
2	S1B	B-Side Source Terminal for Mux 1. Can be an input or output.
3	D1	Drain Terminal for Mux 1. Can be an input or output.
4	D2	Drain Terminal for Mux 2. Can be an input or output.
5	S2B	B-Side Source Terminal for Mux 2. Can be an input or output.
6	S2A	A-Side Source Terminal for Mux 2. Can be an input or output.
7	S3A	A-Side Source Terminal for Mux 3. Can be an input or output.
8	S3B	B-Side Source Terminal for Mux 3. Can be an input or output.
9	D3	Drain Terminal for Mux 3. Can be an input or output.
10	D4	Drain Terminal for Mux 4. Can be an input or output.
11	S4B	B-Side Source Terminal for Mux 4. Can be an input or output.
12	S4A	A-Side Source Terminal for Mux 4. Can be an input or output.
13	S5A	A-Side Source Terminal for Mux 5. Can be an input or output.
14	S5B	B-Side Source Terminal for Mux 5. Can be an input or output.
15	D5	Drain Terminal for Mux 5. Can be an input or output.
16	D6	Drain Terminal for Mux 6. Can be an input or output.
17	S6B	B-Side Source Terminal for Mux 6. Can be an input or output.
18	S6A	A-Side Source Terminal for Mux 6. Can be an input or output.
19	A1	Logic Input. Sets Bit A1 from the least significant bits of the 7-bit slave address.
20	A0	Logic Input. Sets Bit A0 from the least significant bits of the 7-bit slave address.
21	SCL	Digital Input, Serial Clock Line. Open drain input used in conjunction with SDA to clock data into the device. External pull-up resistor required.
22	SDA	Digital I/O. Bidirectional open drain data line. External pull-up resistor required.
23	V_{DD}	Positive Power Supply Input.
24	GND	Ground (0 V) Reference.

TYPICAL PERFORMANCE CHARACTERISTICS

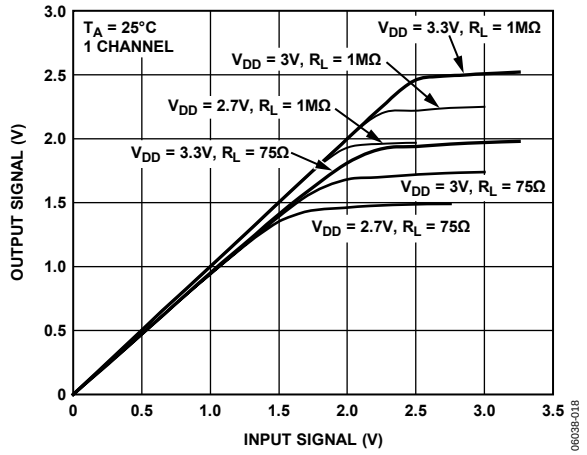


Figure 4. Analog Signal Range with 3 V Supply

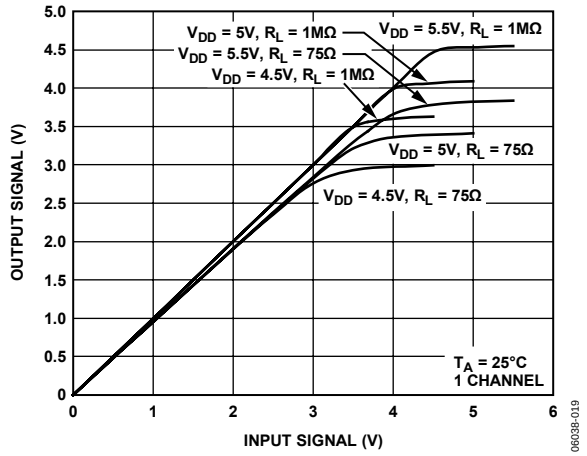


Figure 5. Analog Signal Range with 5 V Supply

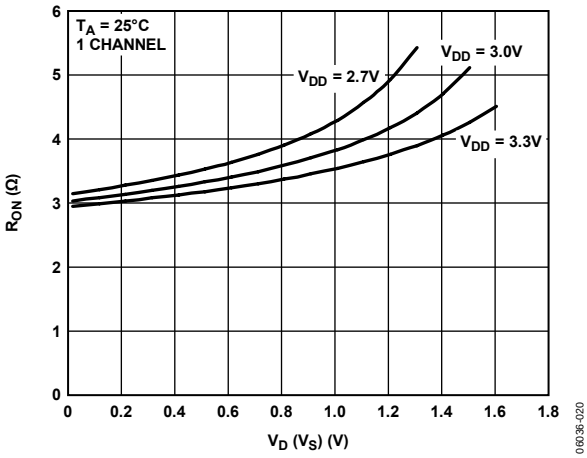


Figure 6. On Resistance vs. V_D (V_S) with 3 V Supply

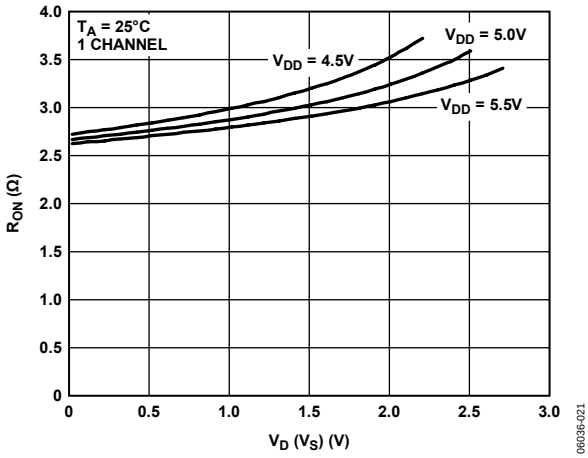


Figure 7. On Resistance vs. V_D (V_S) with 5 V Supply

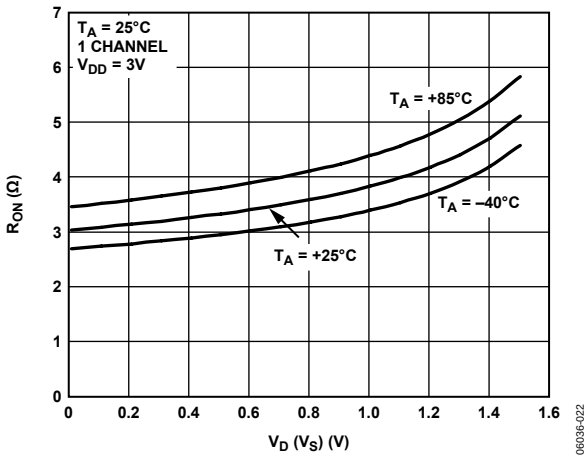


Figure 8. On Resistance vs. V_D (V_S) for Various Temperatures with 3 V Supply

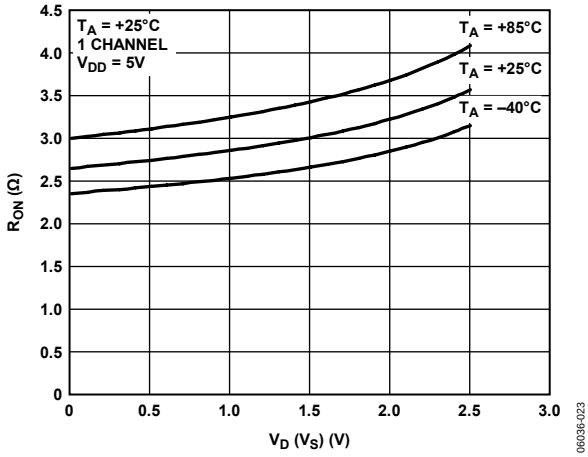


Figure 9. On Resistance vs. V_D (V_S) for Various Temperatures with 5 V Supply

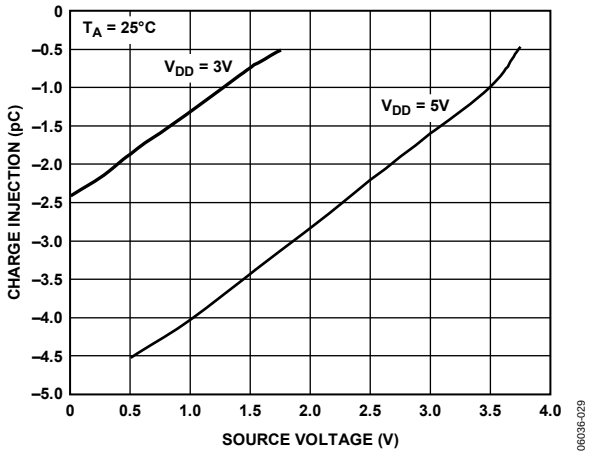


Figure 10. Charge Injection vs. Source Voltage

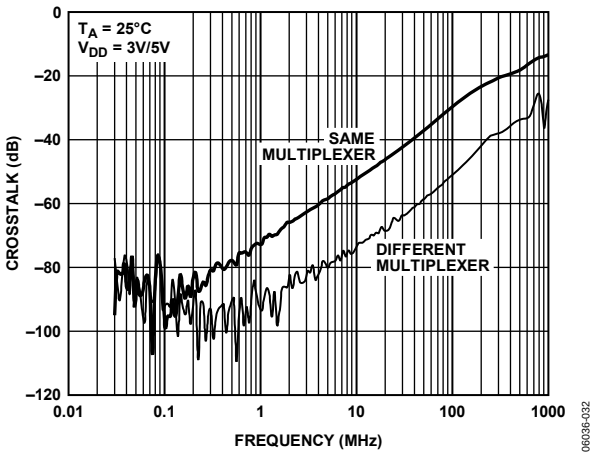


Figure 13. Crosstalk vs. Frequency

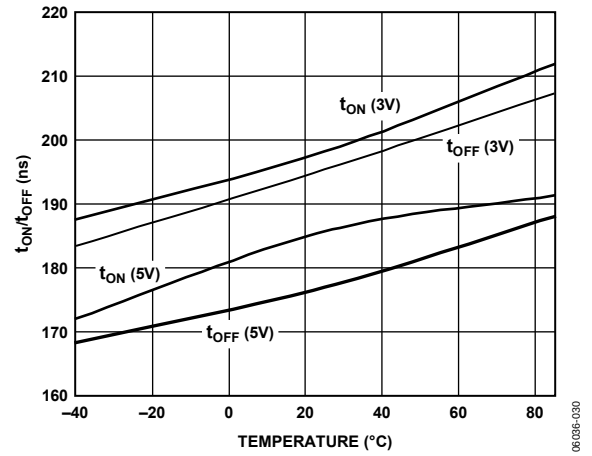


Figure 11. t_{ON}/t_{OFF} vs. Temperature

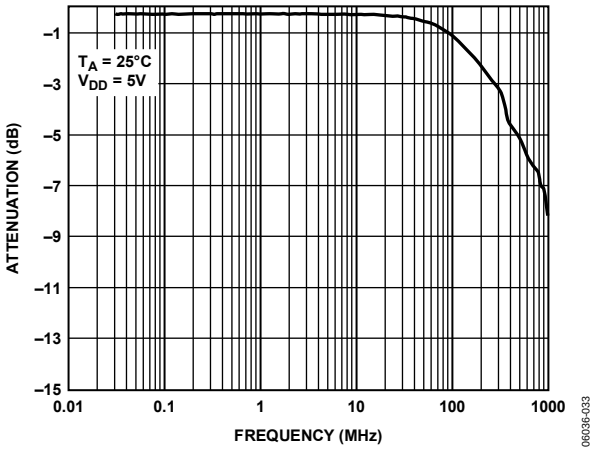


Figure 14. Bandwidth

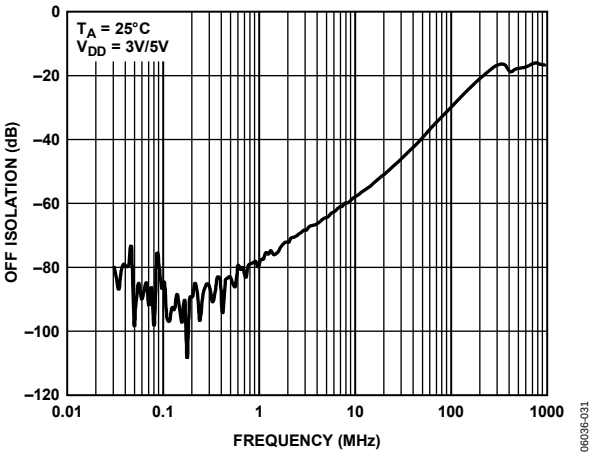


Figure 12. Off Isolation vs. Frequency

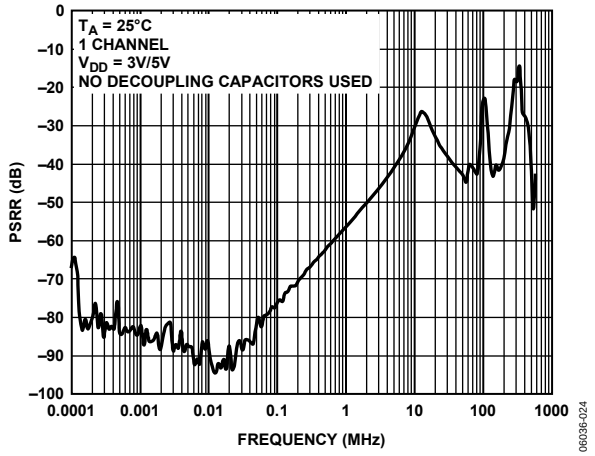


Figure 15. PSRR vs. Frequency

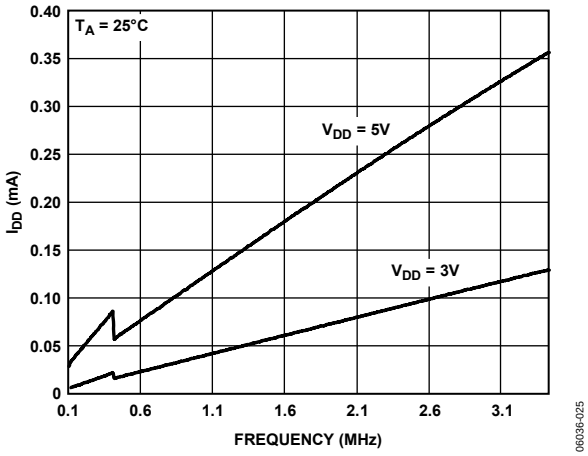


Figure 16. I_{DD} vs. f_{CLK} Frequency

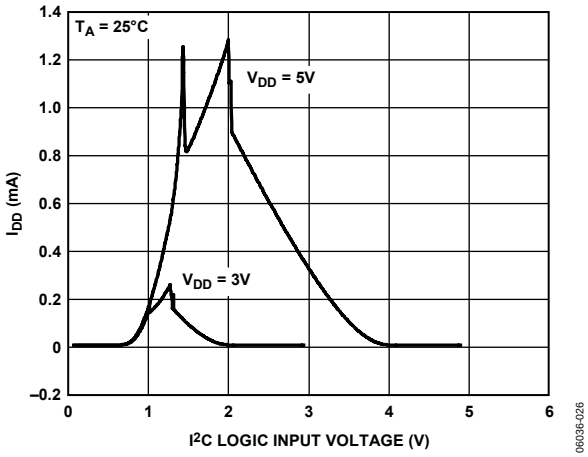


Figure 17 I_{DD} vs. I^2C Logic Input Voltage (SDA, SCL)

TEST CIRCUITS

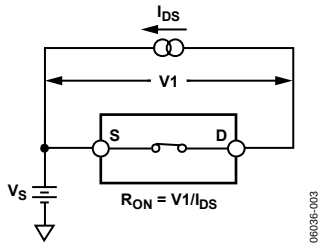


Figure 18. On Resistance

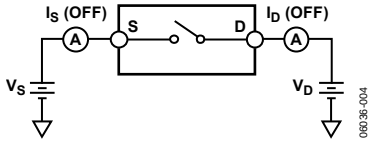


Figure 19. Off Leakage

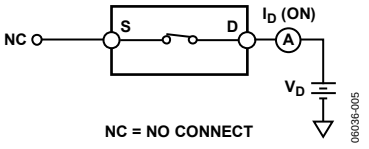


Figure 20. On Leakage

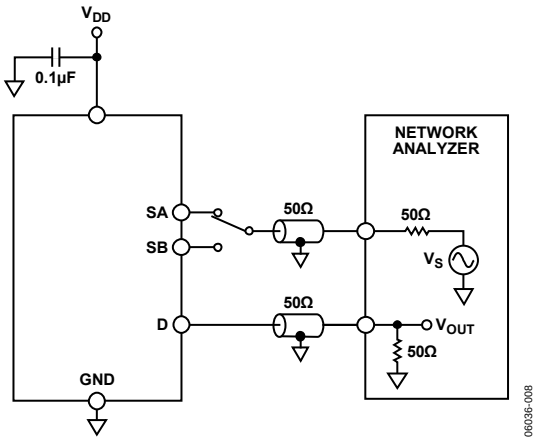


Figure 21. Bandwidth

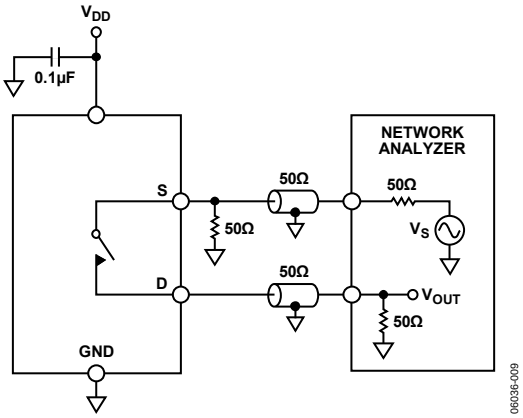


Figure 22. Off Isolation

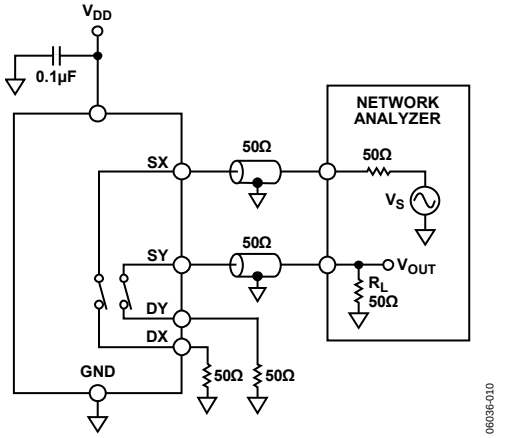


Figure 23. Channel-to-Channel Crosstalk

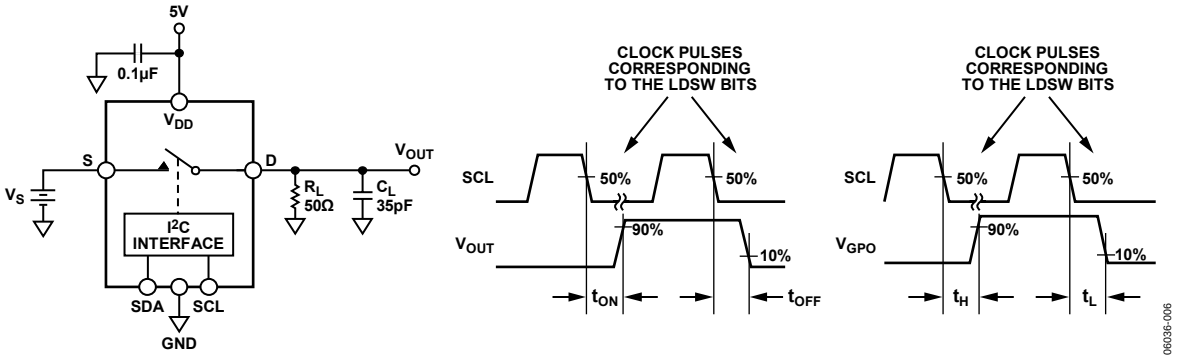


Figure 24. Switching Times

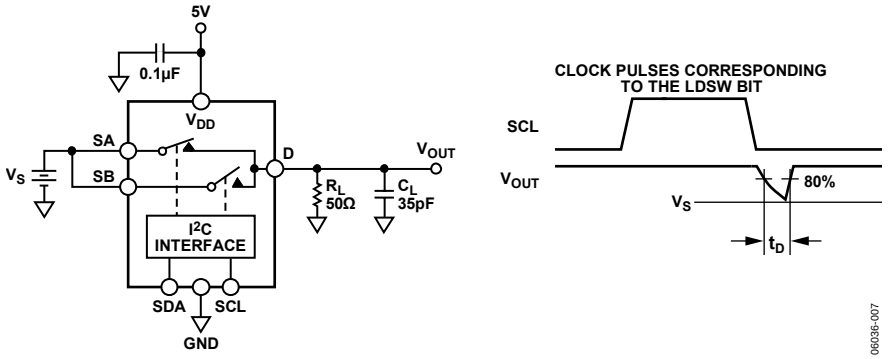


Figure 25. Break-Before-Make Time Delay

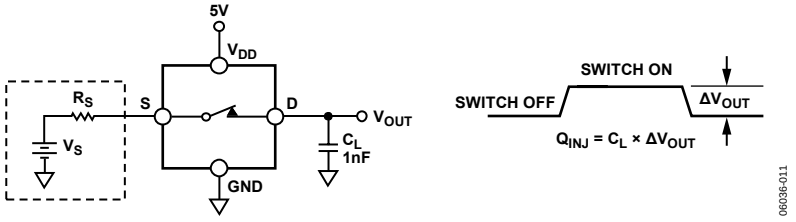


Figure 26. Charge Injection

TERMINOLOGY

On Resistance (R_{ON})
The series on-channel resistance measured between the S pin and D pin.

On Resistance Match (ΔR_{ON})
The channel-to-channel matching of on resistance when channels are operated under identical conditions.

On Resistance Flatness ($R_{FLAT(ON)}$)
The variation of on resistance over the specified range produced by the specified analog input voltage change with a constant load current.

Channel Off Leakage (I_{OFF})
The sum of leakage currents into or out of an off channel input.

Channel On Leakage (I_{ON})
The current loss/gain through an on-channel resistance, creating a voltage offset across the device.

Input Leakage Current (I_{IN}, I_{INL}, I_{INH})
The current flowing into a digital input when a specified low level or high level voltage is applied to that input.

Input/Output Off Capacitance (C_{OFF})
The capacitance between an analog input and ground when the switch channel is off.

Input/Output On Capacitance (C_{ON})
The capacitance between the inputs or outputs and ground when the switch channel is on.

Digital Input Capacitance (C_{IN})
The capacitance between a digital input and ground.

Output On Switching Time (t_{ON})
The time required for the switch channel to close. The time is measured from 50% of the falling edge of the LDSW bit to the time the output reaches 90% of the final value.

Output Off Switching Time (t_{OFF})
The time required for the switch to open. The time is measured from 50% of the falling edge of the LDSW bit to the time the output reaches 10% of the final value.

Total Harmonic Distortion + Noise (THD + N)
The ratio of the harmonic amplitudes plus noise of a signal to the fundamental.

−3 dB Bandwidth
The frequency at which the output is attenuated by 3 dB.

Off Isolation
The measure of unwanted signal coupling through an off switch.

Crosstalk
The measure of unwanted signal that is coupled through from one channel to another because of parasitic capacitance.

Charge Injection
The measure of the glitch impulse transferred from the digital input to the analog output during on/off switching.

Differential Gain Error
The measure of how much color saturation shift occurs when the luminance level changes. Both attenuation and amplification can occur; therefore, the largest amplitude change between any two levels is specified and expressed in %.

Differential Phase Error
The measure of how much hue shift occurs when the luminance level changes. It can be a negative or positive value and is expressed in degrees of subcarrier phase.

Input High Voltage (V_{INH})
The minimum input voltage for Logic 1.

Input Low Voltage (V_{INL})
The maximum input voltage for Logic 0.

Output Low Voltage (V_{OL})
The maximum output voltage for Logic 0.

I_{DD}
Positive supply current.

THEORY OF OPERATION

The ADG796A is a monolithic CMOS device comprising six 2:1 multiplexer/demultiplexers controllable via a standard I²C serial interface. The CMOS process provides ultralow power dissipation, yet offers high switching speed and low on resistance.

The on resistance profile is very flat over the full analog input range, and wide bandwidth ensures excellent linearity and low distortion. These features, combined with a wide input signal range, make the ADG796A the ideal switching solution for a wide range of TV applications.

The switches conduct equally well in both directions when on. In the off condition, signal levels up to the supplies are blocked. The integrated serial I²C interface controls the operation of the multiplexers.

The ADG796A has many attractive features, such as the ability to individually control each multiplexer and the option of reading back the status of any switch through the I²C interface. The following sections describe these features in more detail.

I²C SERIAL INTERFACE

The ADG796A is controlled via an I²C-compatible serial bus interface (refer to the *I²C-Bus Specification* available from Philips Semiconductor) that allows the part to operate as a slave device (no clock is generated by the ADG796A). The communication protocol between the I²C master and the device operates as follows:

1. The master initiates data transfer by establishing a start condition defined as a high-to-low transition on the SDA line while SCL is high. This indicates that an address/data stream follows. All slave devices connected to the bus respond to the start condition and shift in the next eight bits, consisting of a seven bit address (MSB first) plus an R/$\overline{W}$ bit. This bit determines the direction of the data flow during the communication between the master and the addressed slave device.

2. The slave device whose address corresponds to the transmitted address responds by pulling the SDA line low during the ninth clock pulse (this is called the acknowledge bit). At this stage, all other devices on the bus remain idle while the selected device waits for data to be written to, or read from, its serial register. If the R/$\overline{W}$ bit is set high, the master reads from the slave device. However, if the R/$\overline{W}$ bit is set low, the master writes to the slave device.

3. Data transmits over the serial bus in sequences of nine clock pulses (eight data bits followed by an acknowledge bit). The transitions on the SDA line must occur during the low period of the clock signal (SCL) and remain stable during the high period (SCL). This is because a low-to-high transition when the clock signal is high can be interpreted as a stop event, which ends the communication between the master and the addressed slave device.

4. After transferring all data bytes, the master establishes a stop condition, defined as a low-to-high transition on the SDA line while SCL is high. In write mode, the master pulls the SDA line high during the 10th clock pulse to establish a stop condition. In read mode, the master issues a no acknowledge for the ninth clock pulse (the SDA line remains high). The master then brings the SDA line low before the 10th clock pulse, and then high during the 10th clock pulse to establish a stop condition.

I²C ADDRESS

The ADG796A has a seven-bit I²C address. The five most significant bits are internally hardwired while the last two bits, A0 and A1, are user adjustable. This allows the user to connect up to four ADG796As to the same bus. The I²C bit map shows the configuration of the seven-bit address.

Seven-Bit I²C Address Bit Configuration

MSB						LSB
1	0	1	0	0	A1	A0

WRITE OPERATION

When writing to the ADG796A, the user must begin with an address byte and R/$\overline{W}$ bit. Next, the switch acknowledges that it is prepared to receive data by pulling SDA low. Data is loaded into the device as a 16-bit word under the control of a serial clock input, SCL. Figure 27 illustrates the entire write sequence for the ADG796A. The first data byte (AX7 to AX0) controls the status of the switches, while the LDSW and RESETB bits from the second byte control the operation mode of the device.

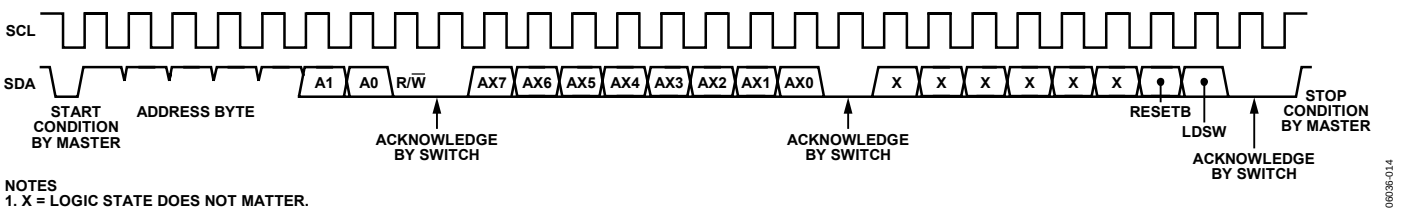


Figure 27. Write Operation

Table 6 shows a list of all commands supported by the ADG796A with the corresponding byte that needs to be loaded during a write operation.

To achieve the desired configuration, one or more commands can be loaded into the device. Any combination of the commands listed in Table 6 can be used with the following restrictions:

- Only one switch from a given multiplexer can be on at any given time.
- When a sequence of successive commands affects the same switch, only the last command is executed.

Table 6. ADG796A Command List

AX7	AX6	AX5	AX4	AX3	AX2	AX1	AX0	Addressed Switch
0	0	0	0	0	0	0	0	S1A/D1, S2A/D2, S3A/D3, S4A/D4, S5A/D5, S6A/D6 off
1	0	0	0	0	0	0	0	S1A/D1, S2A/D2, S3A/D3, S4A/D4, S5A/D5, S6A/D6 on
0	0	0	0	0	0	0	1	S1B/D1, S2B/D2, S3B/D3, S4B/D4, S5B/D5, S6B/D6 off
1	0	0	0	0	0	0	1	S1B/D1, S2B/D2, S3B/D3, S4B/D4, S5B/D5, S6B/D6 on
0	0	0	0	0	0	1	0	S1A/D1 off
1	0	0	0	0	0	1	0	S1A/D1 on
0	0	0	0	0	0	1	1	S1B/D1 off
1	0	0	0	0	0	1	1	S1B/D1 on
0	0	0	0	0	1	0	0	S2A/D2 off
1	0	0	0	0	1	0	0	S2A/D2 on
0	0	0	0	0	1	0	1	S2B/D2 off
1	0	0	0	0	1	0	1	S2B/D2 on
0	0	0	0	0	1	1	0	S3A/D3 off
1	0	0	0	0	1	1	0	S3A/D3 on
0	0	0	0	0	1	1	1	S3B/D3 off
1	0	0	0	0	1	1	1	S3B/D3 on
0	0	0	0	1	0	0	0	S4A/D4 off
1	0	0	0	1	0	0	0	S4A/D4 on
0	0	0	0	1	0	0	1	S4B/D4 off
1	0	0	0	1	0	0	1	S4B/D4 on
0	0	0	0	1	0	1	0	S5A/D5 off
1	0	0	0	1	0	1	0	S5A/D5 on
0	0	0	0	1	0	1	1	S5B/D5 off
1	0	0	0	1	0	1	1	S5B/D5 on
0	0	0	0	1	1	0	0	S6A/D6 off
1	0	0	0	1	1	0	0	S6A/D6 on
0	0	0	0	1	1	0	1	S6B/D6 off
1	0	0	0	1	1	0	1	S6B/D6 on
X[1]	0	0	0	1	1	1	0	Mux 1 disabled (All switches connected to D1 are off)
X[1]	0	0	0	1	1	1	1	Mux 2 disabled (All switches connected to D2 are off)
X[1]	0	0	1	0	0	0	0	Mux 3 disabled (All switches connected to D3 are off)
X[1]	0	0	1	0	0	0	1	Mux 4 disabled (All switches connected to D4 are off)
X[1]	0	0	1	0	0	1	0	Mux 5 disabled (All switches connected to D5 are off)
X[1]	0	0	1	0	0	1	1	Mux 6 disabled (All switches connected to D6 are off)
X[1]	0	0	1	0	1	0	0	Reserved
0	0	0	1	1	1	1	1	All muxes disabled
1	0	0	1	1	1	1	1	Reserved

[1] X= Logic state does not matter.

LDSW BIT

The LDSW bit allows the user to control the way the device executes the commands loaded during write operations. The ADG796A executes all commands loaded between two successive write operations that have set the LDSW bit high.

Setting the LDSW high for every write cycle ensures that the device executes the command immediately after the LDSW bit is loaded into the device. This setting can be used when the desired configuration is achieved by sending a single command or when the switches are not required to be updated at the same time. When the desired configuration requires multiple commands with simultaneous updates, the LDSW bit should be set low while loading the commands, except for the last one when the LDSW bit should be set high. Once the last command with LDSW = high is loaded, the device simultaneously executes all commands received since the last update.

POWER ON/SOFTWARE RESET

The ADG796A has a software reset function implemented by the RESETB bit from the second data byte loaded into the device during a write operation. For normal operation of the multiplexers, this bit should be set high. When RESETB = low or after power-up, the switches from all multiplexers are turned off (open).

READ OPERATION

When reading data back from the ADG796A, the user must begin with an address byte and R/$\overline{W}$ bit. Then, the switch acknowledges that it is prepared to transmit data by pulling SDA low. Following this acknowledgement, the ADG796A transmits two bytes on the next clock edges. These bytes contain the status of the switches, and each byte is followed by an acknowledge bit. A logic high bit represents a switch in the on (close) state while a low represents a switch in the off (open) state. Figure 28 illustrates the entire read sequence.

The bit map accompanying Figure 28 shows the relationship between the elements of the ADG796A and the bits that represent their status after a completed read operation.

ADG796 Bit Map

RB15	RB14	RB13	RB12	RB11	RB10	RB9	RB8	RB7	RB6	RB5	RB4	RB3	RB2	RB1	RB0
S1A/D1	S1B/D1	S2A/D2	S2B/D2	S3A/D3	S3B/D3	S4A/D4	S4B/D4	S5A/D5	S5B/D5	S6A/D6	S6B/D6	-	-	-	-

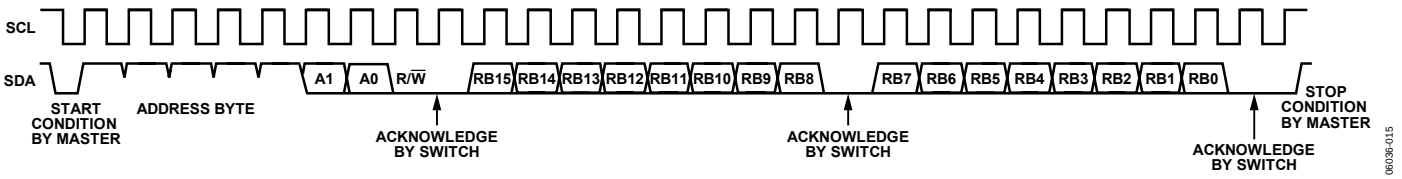


Figure 28. Read Operation

EVALUATION BOARD

The EVAL-ADG796AEB allows designers to evaluate the high performance of the device with a minimum of effort.

This evaluation kit includes a printed circuit board populated with the ADG796A. The evaluation board interfaces to the USB port of a PC or can be used as a standalone evaluation board. Software is available with the evaluation board that allows the user to easily program the ADG796A through the USB port. Schematics of the evaluation board are shown in Figure 29 and Figure 30. The software runs on any PC that has Microsoft® Windows® 2000 or Windows XP installed with a minimum screen resolution of 1200 × 768.

USING THE ADG796A EVALUATION BOARD

The ADG796A evaluation kit is a test system designed to simplify the evaluation of the device. Each input/output of the part comes with a socket specifically chosen for easy audio/video evaluation. A data sheet is also available with the evaluation board offering full information on how to operate the evaluation board.

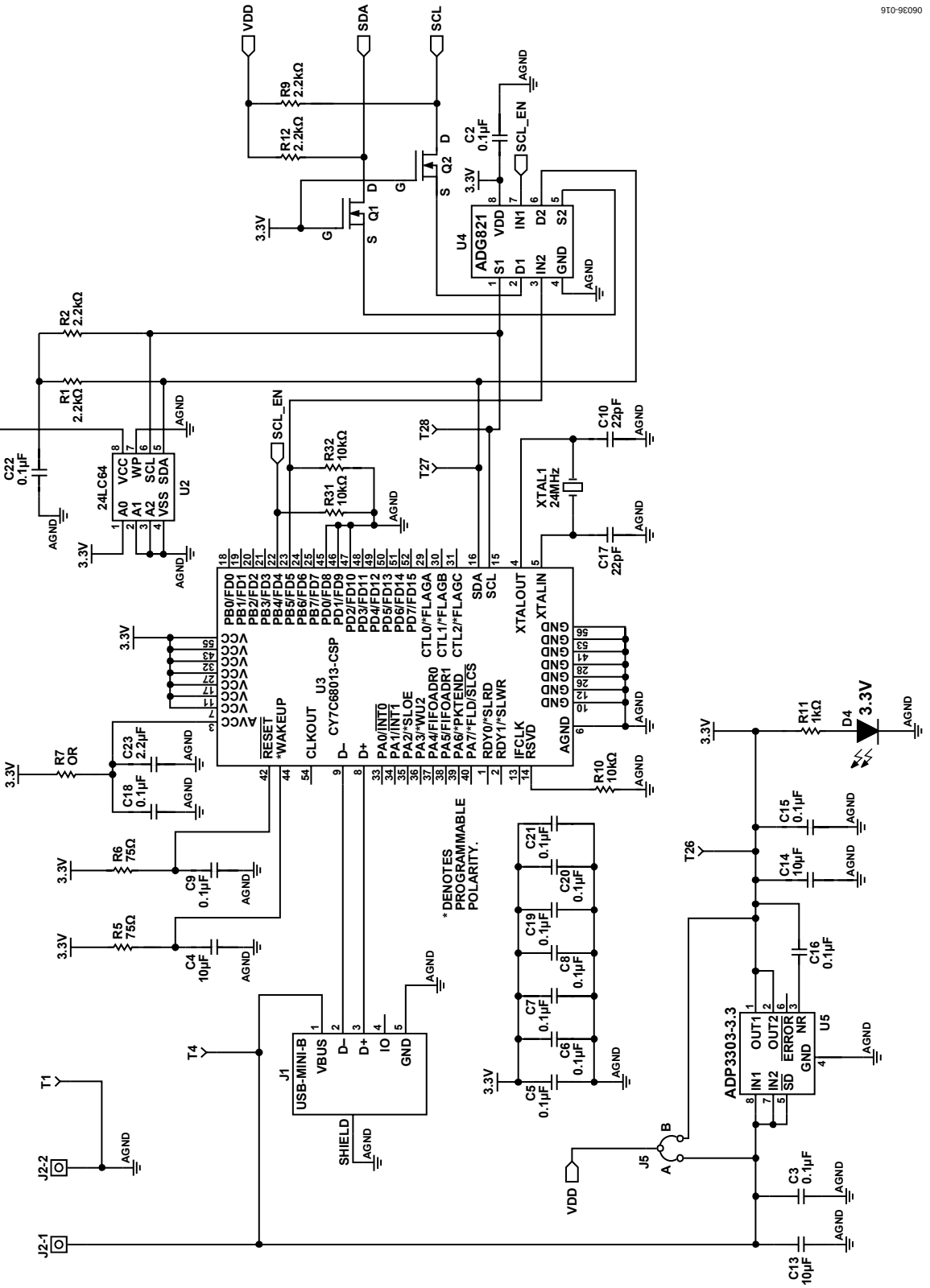


Figure 29. EVAL-ADG796AEB Schematic, USB Controller Section

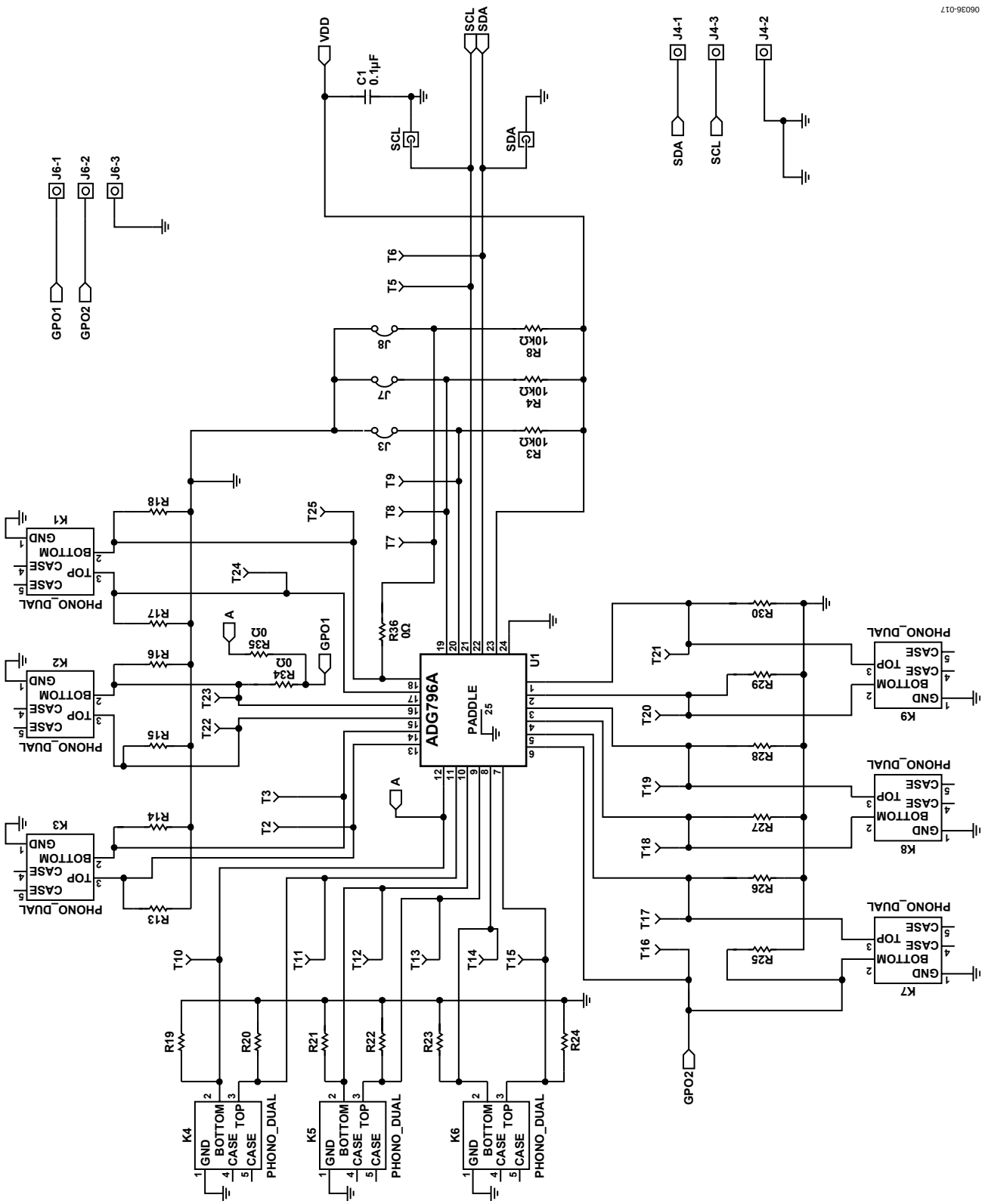
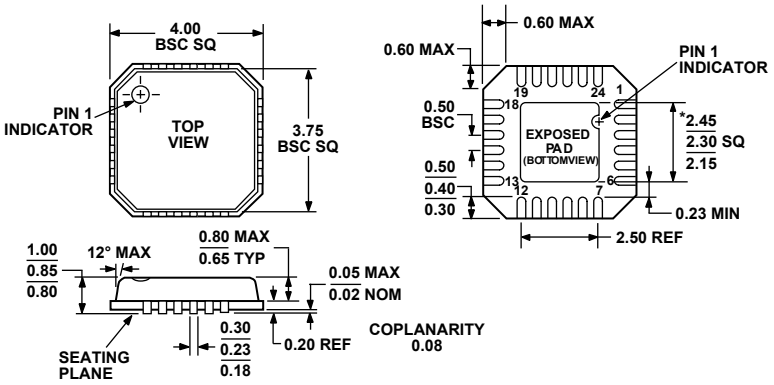


Figure 30. EVAL-ADG796AEB Schematic, Chip Section

OUTLINE DIMENSIONS



*COMPLIANT TO JEDEC STANDARDS MO-220-VGGD-2
EXCEPT FOR EXPOSED PAD DIMENSION

Figure 31. 24-Lead Lead Frame Chip Scale Package [LFCSP_VQ]
4 mm × 4 mm Body, Very Thin Quad
(CP-24-2)
Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	I²C Speed	Package Description	Package Option
ADG796ABCPZ-REEL[1]	−40°C to +85°C	100 kHz, 400 kHz	24-Lead LFCSP_VQ	CP-24-2
ADG796ABCPZ-500RL7[1]	−40°C to +85°C	100 kHz, 400 kHz	24-Lead LFCSP_VQ	CP-24-2
ADG796ACCPZ-REEL[1]	−40°C to +85°C	100 kHz, 400 kHz, 3.4 MHz	24-Lead LFCSP_VQ	CP-24-2
ADG796ACCPZ-500RL7[1]	−40°C to +85°C	100 kHz, 400 kHz, 3.4 MHz	24-Lead LFCSP_VQ	CP-24-2
EVAL-ADG796AEB[2]			Evaluation Board	

[1] Z = Pb-free part.
[2] Evaluation board is RoHS compliant.

NOTES

Purchase of licensed I²C components of Analog Devices or one of its sublicensed Associated Companies conveys a license for the purchaser under the Philips I²C Patent Rights to use these components in an I²C system, provided that the system conforms to the I²C Standard Specification as defined by Philips.

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